

# A 65nm CMOS Comparator with Modified Latch to Achieve 7GHz/1.3mW at 1.2V and 700MHz/47 $\mu$ W at 0.6V

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# Outline

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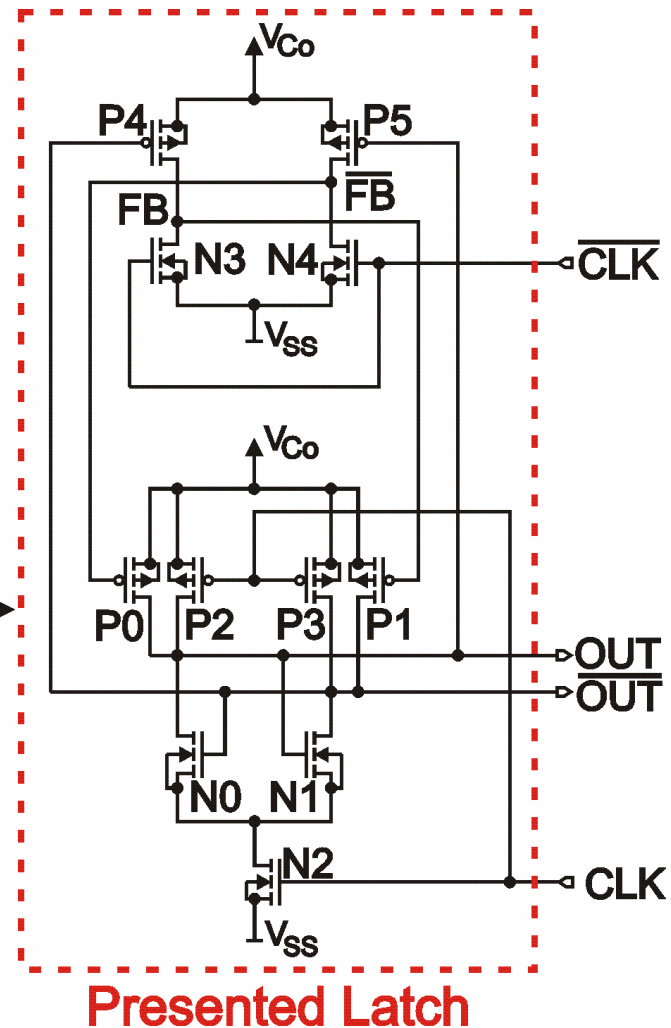
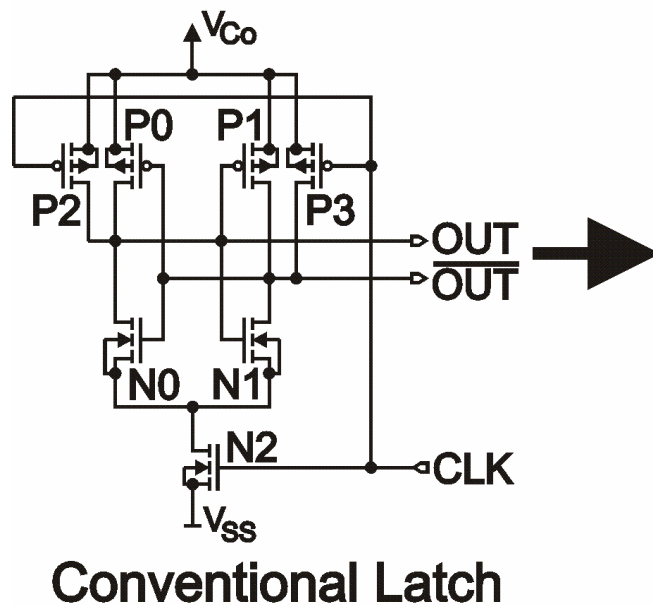
# Introduction: motivation for fast, low-power, low voltage comparators

- Low supply voltages in modern CMOS processes
- Low power consumption for mobile devices
- Flash ADCs:  
parallel clocked, mostly regenerative comparators
  - > low power consumption
  - > small chip area needed per comparator
  - > pre-amplifiers are added in front of the comparator to enhance resolution
- Data receivers/repeaters
- Latch-type sense amplifiers in memories

# Schematic of the comparator

Splitting up of a conventional latch into two paths between the supply rails:

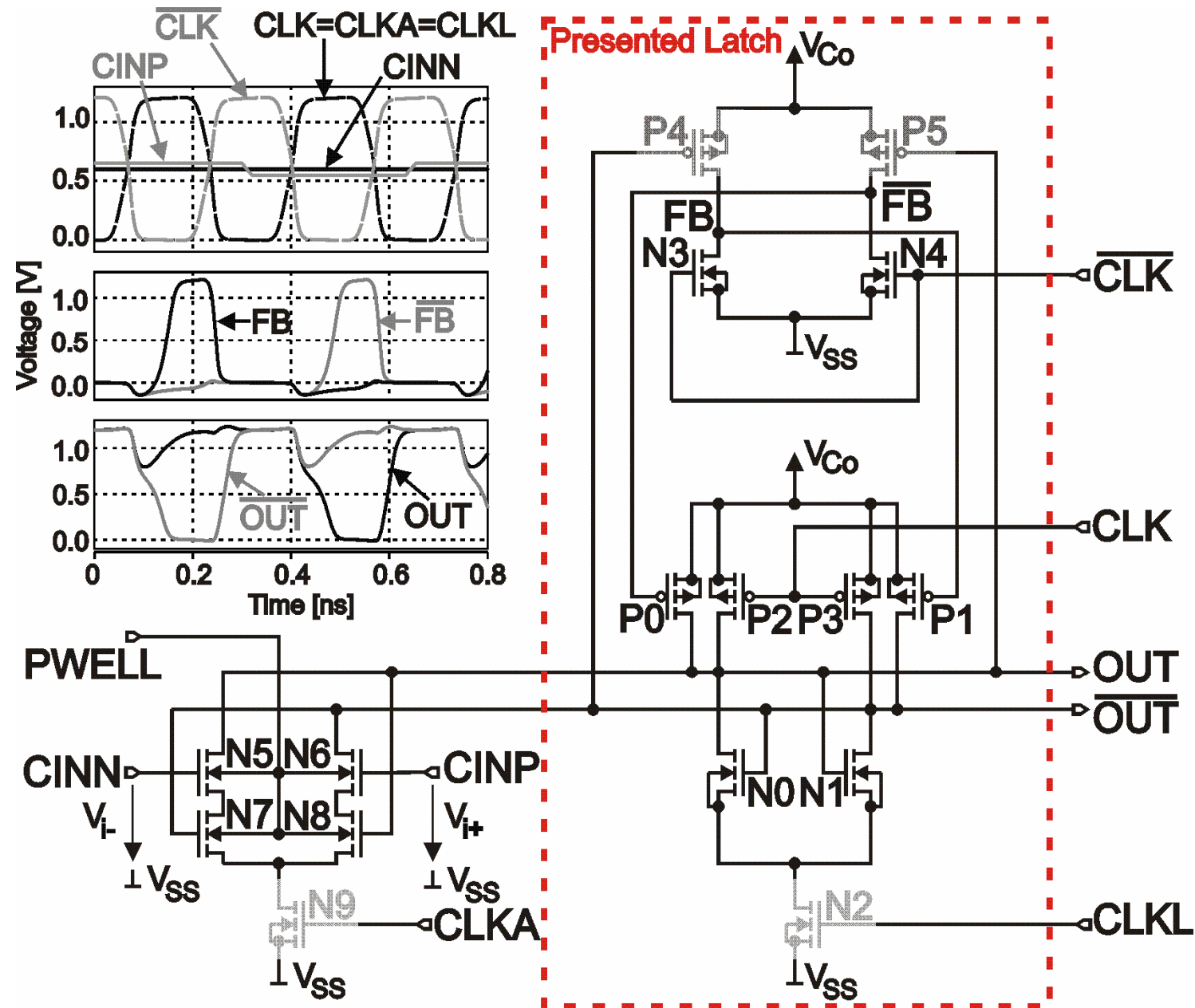
-> Advantage: **Fast operation at a low supply voltage without needing static current**



# Schematic of the comparator

## Reset phase:

- $\text{CLK} = \text{CLKA} = \text{CLKL}$  at  $V_{ss}$
- $\text{OUT}$  and  $\overline{\text{OUT}}$  are pulled up to  $V_{Co}$
- $\text{FB}$  and  $\overline{\text{FB}}$  are pulled down to  $V_{ss}$



# Schematic of the comparator

## Comparison phase:

- $\text{CLK} = \text{CLKA} = \text{CLKL}$  at  $V_{Co}$

## Case $V_{i+} > V_{i-}$ :

- pos. feedback:

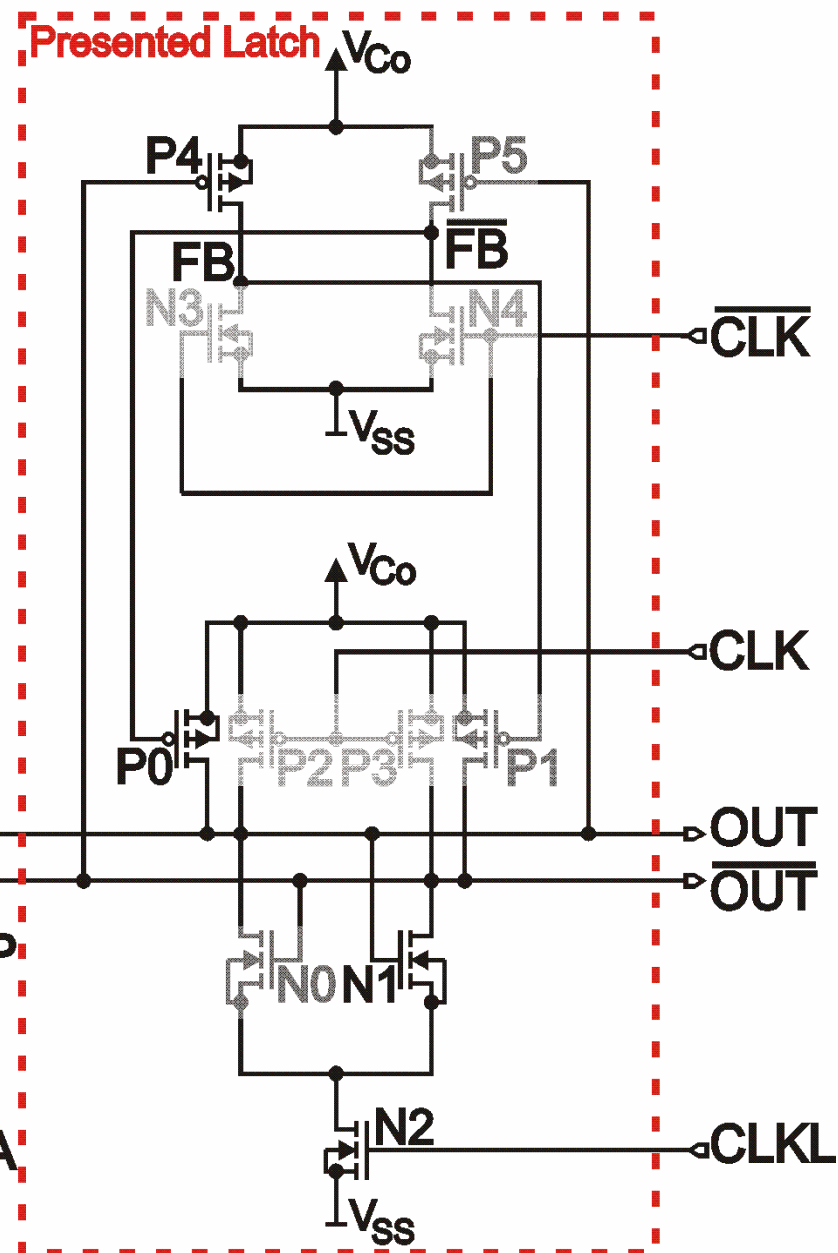
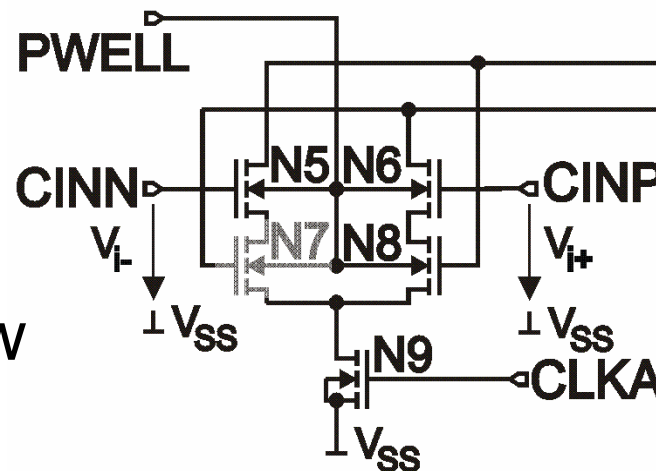
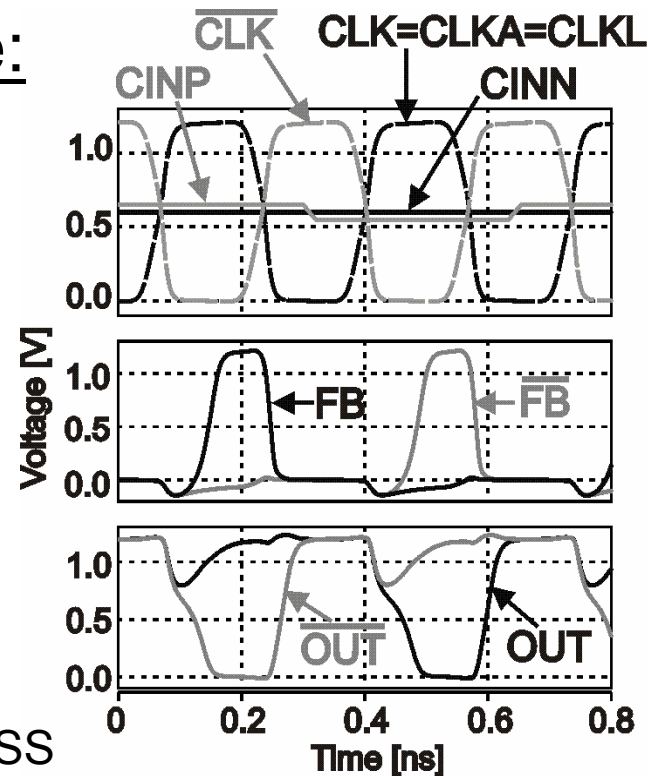
$\text{FB} \rightarrow V_{Co}$

$\overline{\text{FB}}$  stays near  $V_{SS}$

$\text{OUT} \rightarrow V_{Co}$

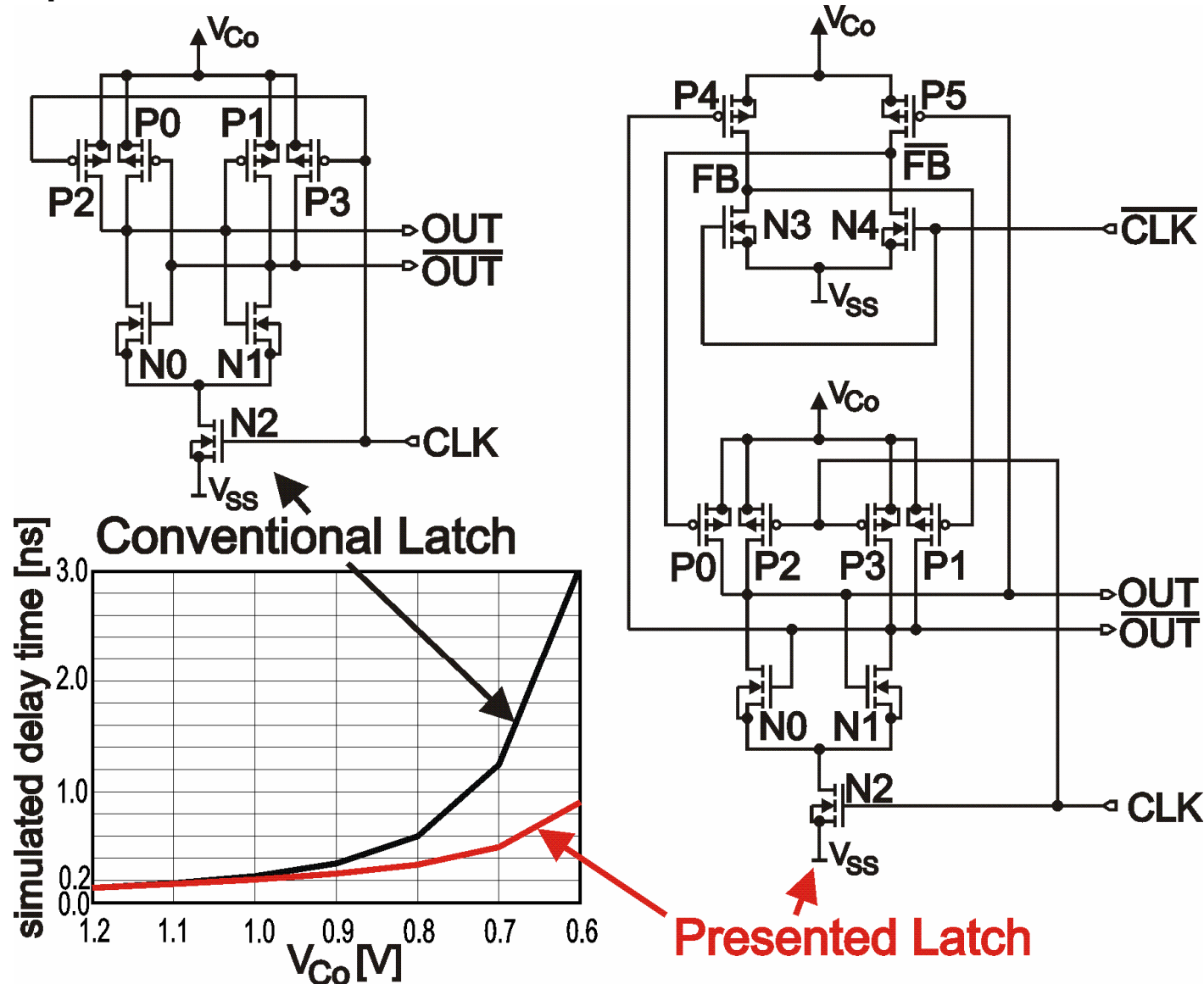
$\overline{\text{OUT}} \rightarrow V_{SS}$

- N7, N8 avoids static current flow after decision

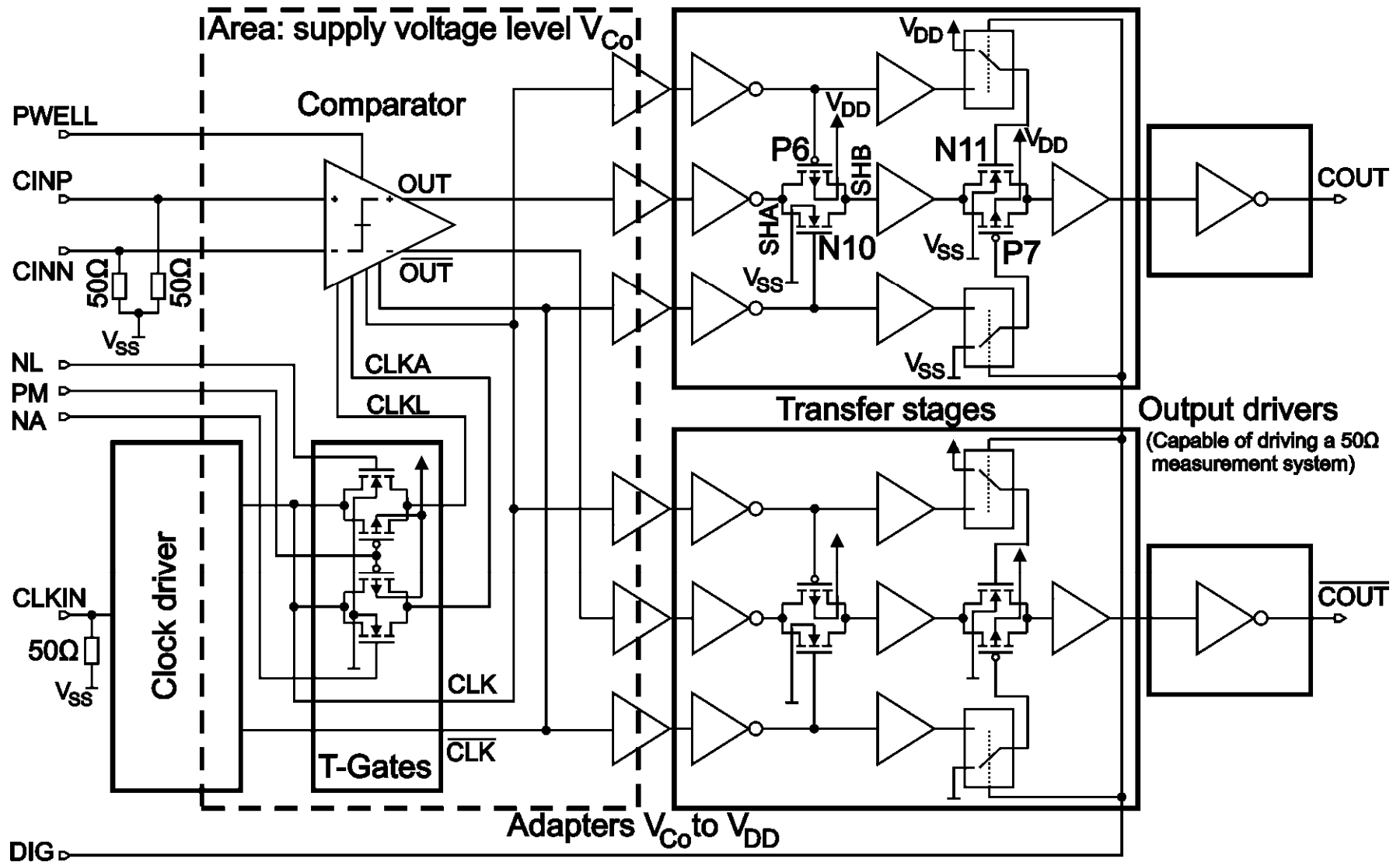


# Schematic of the comparator

Comparison of the conventional latch with the presented latch:



# Block diagram of the test chip

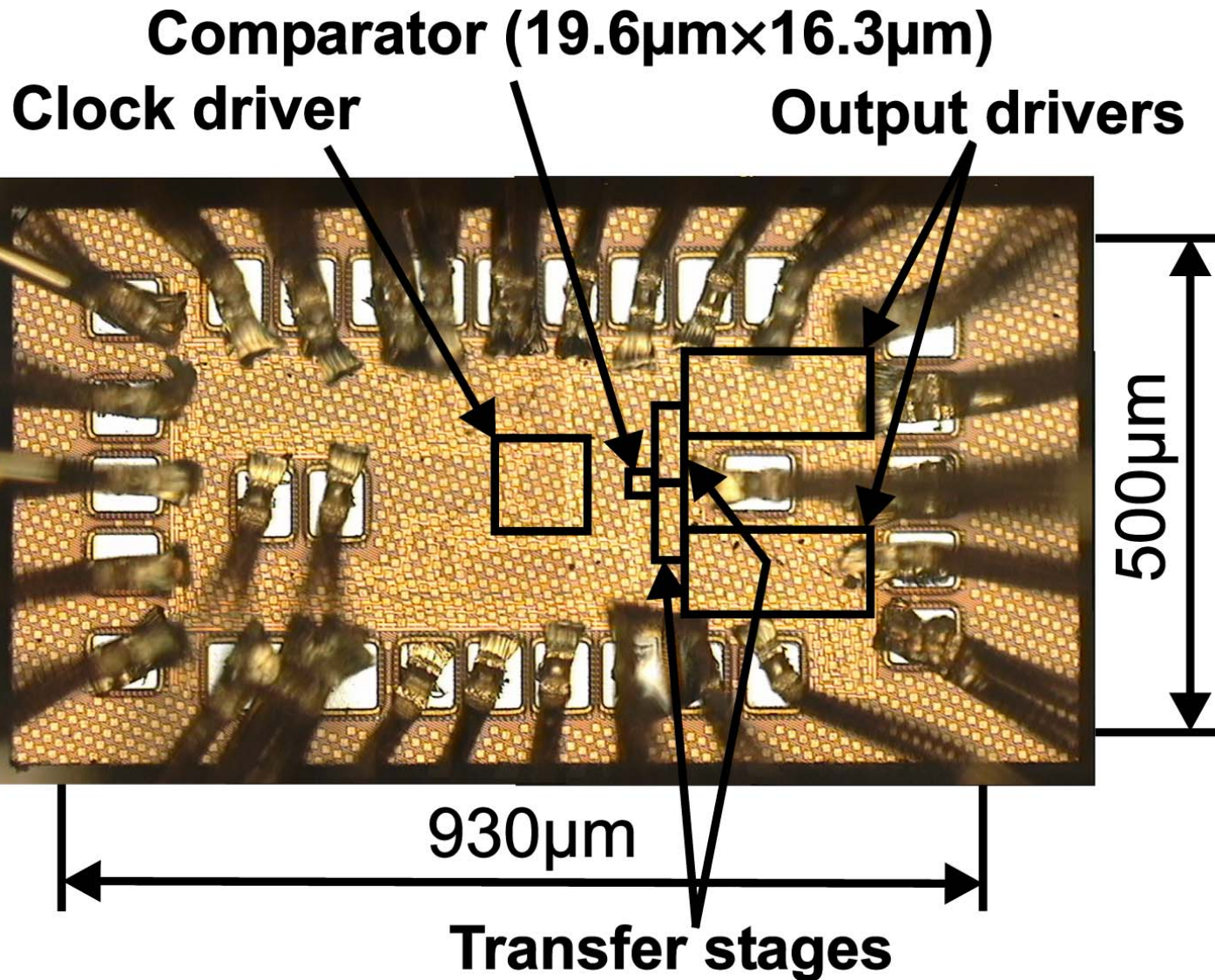


T-Gates: For sensitivity tuning at lower clock rates [6]

[6] *IEEE ESSCIRC*, pp. 408-411, 2007

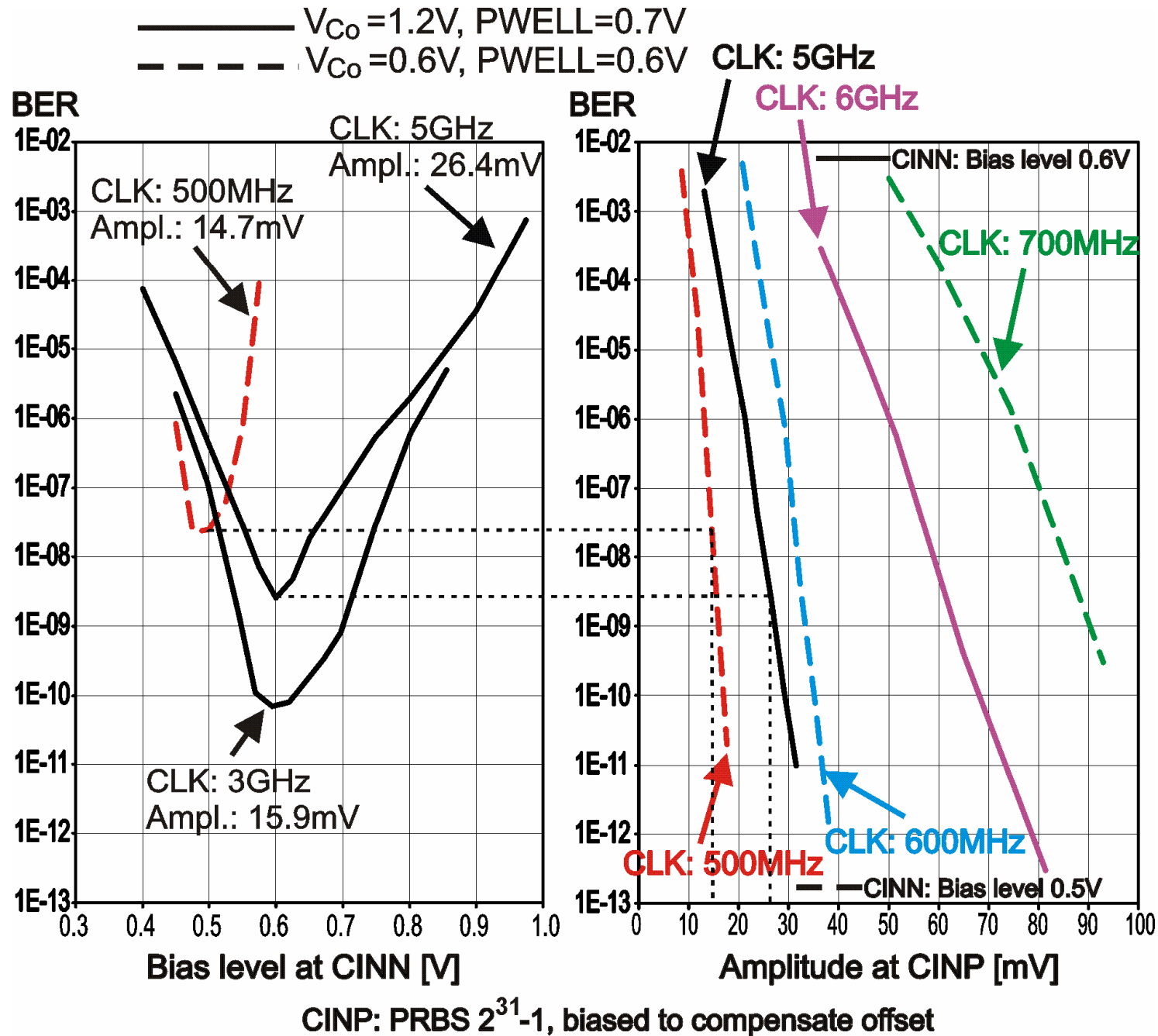


# Micrograph of the test chip



Technology: Low-Power 65nm/1.2V CMOS process

# Measurement results: BER

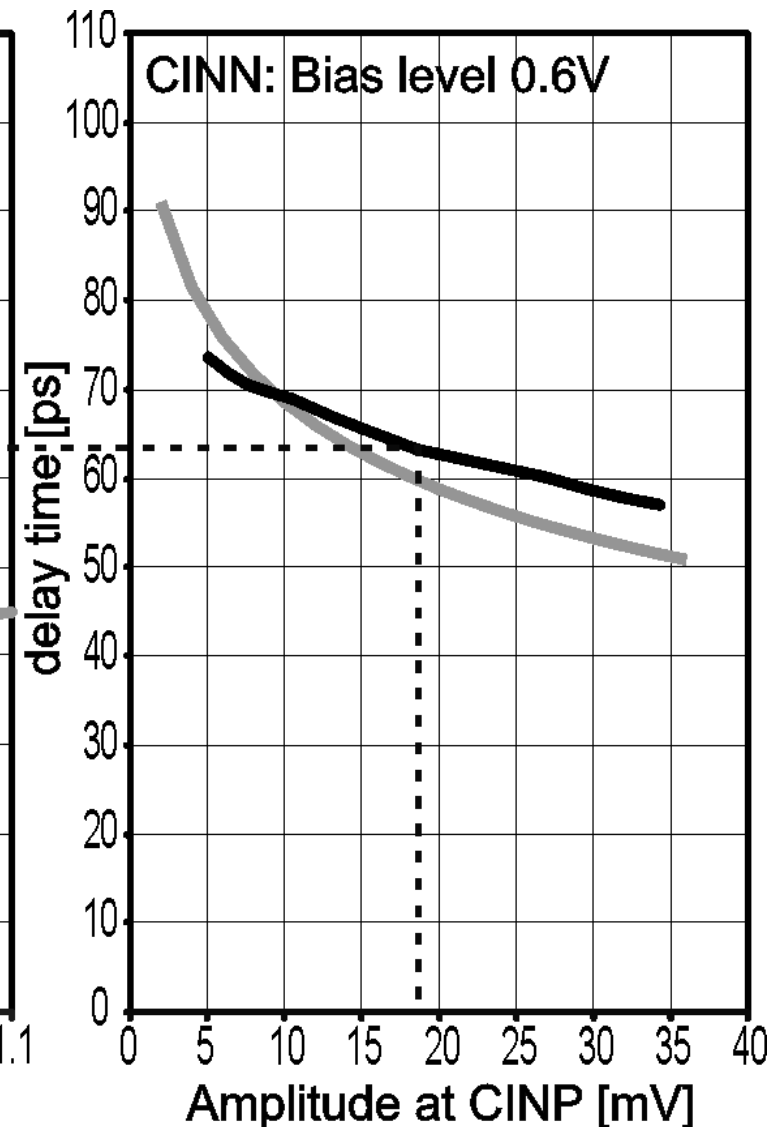
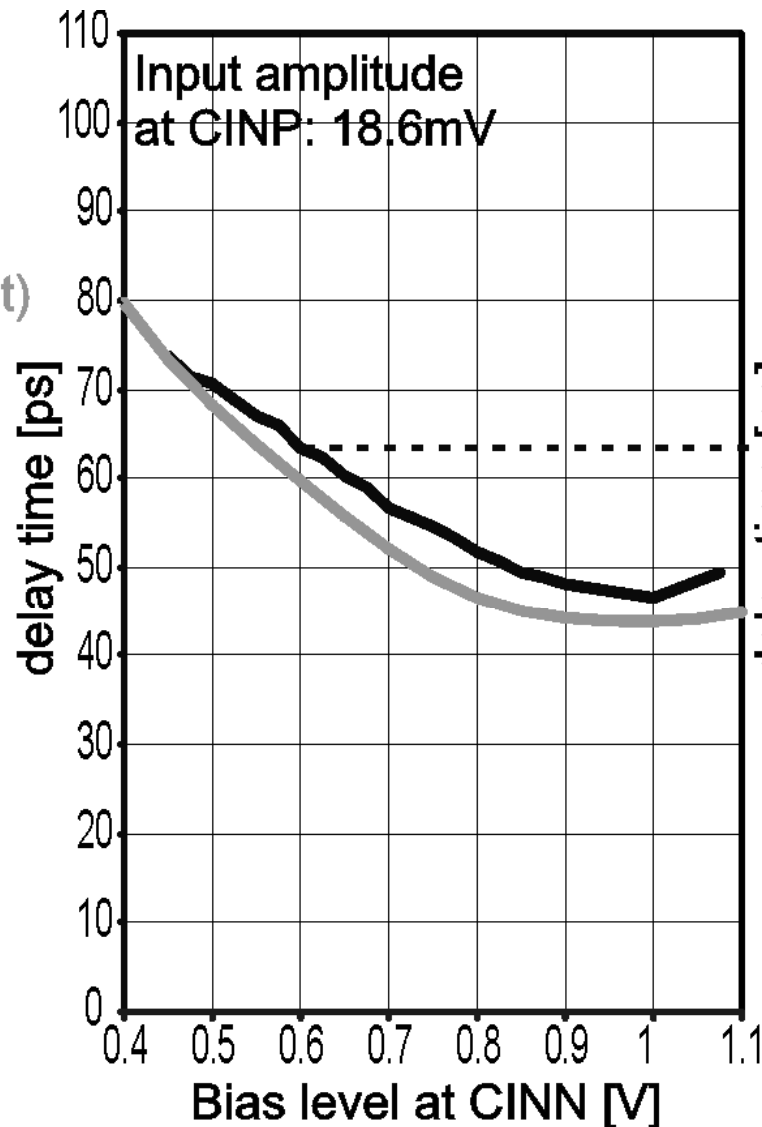


# Measurement results

Delay time (time shift between CLK and  $\overline{\text{OUT}}$ ) of the comparator

$V_{\text{Co}} = V_{\text{DD}} = 1.2\text{V}$   
 $\text{PWELL} = 0.7\text{V}$

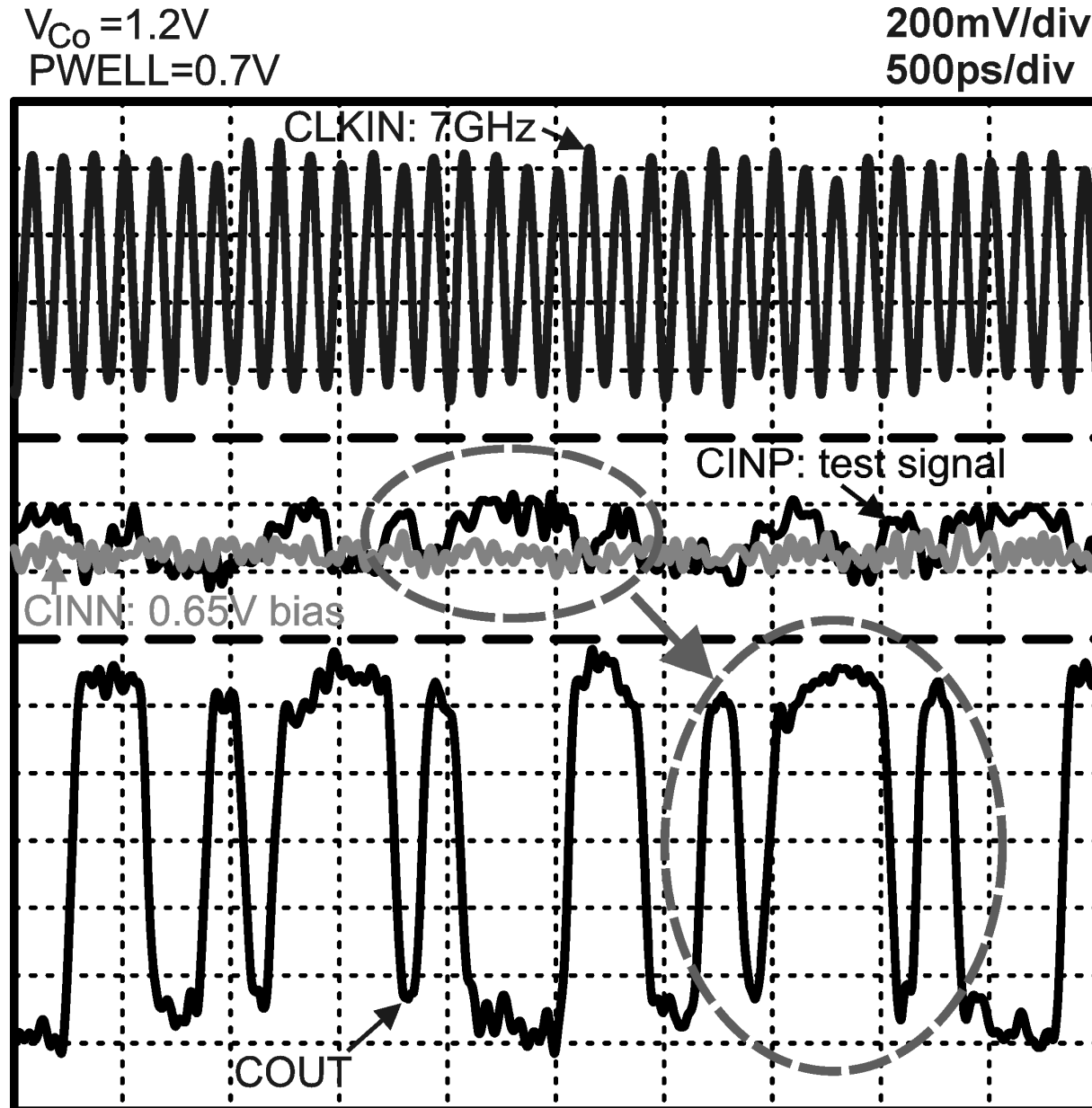
— measured  
— simulated  
(post-layout)



CINP: rectangular signal, biased to compensate offset

# Measurement results

Oscilloscope screenshots at 7GHz clock and  $V_{Co}=1.2V$



# Key data of the comparator at a glance

- Technology: 65nm Low-Power CMOS ( $V_t \approx 0.4V$ )
- Maximum clock frequency: 700MHz @  $V_{Co}=0.6V$   
7GHz @  $V_{Co}=1.2V$
- Minimum input voltage difference to achieve a  $BER < 10^{-9}$ :
  - $V_{Co}=0.6V$ : 16mV @ 500MHz, 90.2mV @ 700MHz
  - $V_{Co}=1.2V$ : 15mV @ 3GHz, 20mV @ 4GHz  
(sensitivity tuning @ 3GHz and @ 4GHz),  
27.2mV @ 5GHz, 63mV @ 6GHz,  
281mV @ 7GHz
- Power consumption: 47 $\mu$ W @ 0.6V/700MHz  
1.3mW @ 1.2V/7GHz
- Offset:  $\sigma=22mV$  @ 1.2V,  $\sigma=47mV$  @ 0.6V (simulation)
- Size of comparator: 19.6 $\mu$ m $\times$ 16.3 $\mu$ m

# Comparison

Techn.	Supply voltage	Clock	Sensitivity BER=10 <sup>-9</sup>	Power cons.	Offset ( $\sigma$ )	Ref.
0.13 $\mu$ m CMOS	1.5V	n.m.	n.m.	n.m.	8.5mV	[2]
0.18 $\mu$ m CMOS	1.8V	1.4GHz	n.m.	350 $\mu$ W	29.7mV w/o offset comp.	[3]
90nm CMOS	1.2V	2GHz meas. 3GHz sim.	inp. noise $\sigma_n=1.5$ mV	225 $\mu$ W @2GHz	8mV	[4]
0.12 $\mu$ m CMOS $V_t \approx 0.29$ V	1.5V	6GHz	29.4mV @5GHz	2.65mW @6GHz	23mV sim.	[5]
	0.5V	0.6GHz	60.5mV @0.6GHz	18 $\mu$ W	57mV sim.	
0.12 $\mu$ m CMOS	1.5V	3GHz	9.2mV @3GHz	584 $\mu$ W @3GHz	16.1mV sim.	[6]
65nm LP-CMOS $V_t \approx 0.4$ V	1.2V	7GHz	15mV @3GHz 27.2mV @5GHz	1.3mW @7GHz	22mV sim.	This work
	0.6V	0.7GHz	16mV @0.5GHz 90.2mV @0.7GHz	47 $\mu$ W @0.7GHz	47mV sim.	

[2] *IEEE JSSC*, vol. 39, pp. 1148-1158, 2004.

[4] *IEEE ISSCC*, pp. 314-315, 2003.

[6] *IEEE ESSCIRC*, pp. 408-411, 2007.

[3] *IEEE JSSC*, vol. 39, pp. 837-840, 2004.

[5] *IEEE ISSCC*, pp. 316-317, 2003.

Thank you for your attention !

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For additional multimedia material: See <http://www.isscc.org>

